Issue Classification

Application/Control No.	Applicant(s)/Patent Under Reexamination
10603746	CHANG, JEOM-JIN
Examiner	**Art Unit**
Wyszynski, Aubrey H	2134

ORIGINAL

CLASS	SUBCLASS
726	28

CROSS REFERENCE(S)

CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
713	1	193	2		
714	36				

INTERNATIONAL CLASSIFICATION

CLAIMED	NON-CLAIMED
G 06 F 21 / 00 (2006.01.01)	
G 06 F 7 / 04 (2006.01.01)	
G 06 K 9 / 00 (2006.01.01)	

Wyszynski, Aubrey H (Assistant Examiner)	12/5/07 (Date) AHW	GILBERTO BARRON JR SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100	Total Claims Allowed: 14
JK Harvo (Legal Instruments Examiner)	12/7/07 (Date)	Kambiz Zand (Primary Examiner)	12/10/07 (Date)

O.G. Print Claim(s)	O.G. Print Figure
1	1